S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/604,328	BLANCO ET AL.	
Examiner	Art Unit	
Nitio C Ratal	2116	

	SEAR	CHED	
Class	Subclass	Date	Examiner
713	300,320,3 23,324,33 0,340	6/17/2006	NCP
716	1,7	6/17/2006	NCP
327	333-334,5 <i>46</i> <i>427, 524,5</i> 55	6/17/2006	NCP
438		- 6/17/2006	NCP

INTERFERENCE SEARCHED		
Subclass	Date	Examiner
ABOVE	6/17/2006	NCP
	Subclass	Subclass Date

SEARCH NO (INCLUDING SEARCH		
	DATE	EXMR
EAST 2.0.3 USPAT, USOCR, US- PGPUB, IBM_TDB, EPO, JPO, DERWENT (See search report)	6/17/2006 }	NCP
Inventor name search	6/17/2006	NCP
NPL Search: IEEE Explorer	6/17/2006	NCP
ACM Digital library	6/17/2006	NCP